

<b>Notice of References Cited</b>	Application/Control No. 10/578,717		Applicant(s)/Patent Under Reexamination HOLTMAN ET AL.	
	Examiner HENOK G. HEYI		Art Unit 2627	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0039470 A1	02-2003	Otsuka et al.	386/95
*	B	US-2006/0013088 A1	01-2006	Fontijn et al.	369/047.32
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
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	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

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	N					
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#### NON-PATENT DOCUMENTS

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